



DEFENSE LOGISTICS AGENCY
DEFENSE SUPPLY CENTER, COLUMBUS
POST OFFICE BOX 3990
COLUMBUS, OH 43218-3990

IN REPLY
REFER TO

DSCC-VQC-09-017451/ (Mr. Grammens/614-692-0604/mpg)

Feb 19, 2009

SUBJECT: Transfer of ESD classification test capability TM 3015 from
Silicon Turnkey Solutions to Hi-Reliability Labs, FSC 5962

Mr. Michael Heddlesten
Quality Assurance Manager
Hi-Reliability Microelectronics
5452 Betsy Ross Dr.
Santa Clara, CA 95054

Dear Mr. Heddlesten:

This letter supersedes DSCC-VQC-08-015425. Hi-Reliability Microelectronics laboratory suitability listing now includes MIL-STD-883 TM 3015 Electrostatic Discharge Sensitivity Classification testing. This is based on review of the procedures and self audit in conjunction with the current suitability of Silicon Turnkey Solutions from which part of the process was transferred. Therefore your laboratory at 5452 Betsy Ross Drive Santa Clara, CA 95054 is considered suitably equipped to perform the MIL-STD-883 tests (reference updated enclosure) on monolithic microcircuits in accordance with the requirements of military specifications MIL-PRF-38535 and MIL-STD-883.

Your laboratory is to maintain a record for all microcircuit testing and submit a summary annually to DSCC-VQC which will include the following as a minimum:

- a. Military part number, SMD, or 883 identification
- b. Date code
- c. Quantity tested
- d. Manufacturer
- e. Manufacturer's lot number
- f. Test method(s)/condition(s)
- g. Date test completed
- h. Qualification test report number as applicable
- i. Self audit reports with deficiencies and corrective actions

The standard reporting period is from May 1 through April 30. Your present reporting period is from May 1, 2008 through April 30, 2009 and is due by 30 June 2009.



Test labs shall notify the qualifying activity immediately after learning of a potential issuance of a GIDEP alert, problem advisory or major quality/reliability problem on their military products utilizing the test methods on the attached enclosure. Failure to provide prior notification may be grounds for removal from DSCC's Commercial Lab Suitability Listing.

This laboratory suitability is valid subject to the conditions as stated in DoD 4120.24-M and SD-6. All processing procedures will incorporate the handling, testing, and packaging requirements according to the guidelines in JEDEC Publication 108 and EIA-STD-5. This laboratory suitability is valid until withdrawn by DSCC-VQC.

If you have any questions, please contact Mr. Michael Grammens at (614) 692-0604.

Sincerely,

A handwritten signature in black ink that reads "Michael S. Adams". The signature is written in a cursive style with a large initial "M".

MICHAEL S. ADAMS
Chief
Custom Devices Branch

Enclosure

cc: VQC (Scott Thomas)
cc: VQC (Alberta Petruskevich)

<u>TEST</u>	<u>METHOD/CONDITION</u>
Insulation Resistance	1003/(A-E, 600V, 100 na)
Moisture Resistance	1004
Steady State Life Test	1005/(A-E, Ta,Tc)
Stabilization Bake	1008/(A-D)
Salt Atmosphere	1009/(A-D)
Temperature Cycling	1010/(A-C)
Thermal Shock	1011/(A-C)
Seal	1014/(A ₁ , A ₂ , C ₁)
Burn-in	1015/(A-D, Ta, Tc)
Constant Acceleration	2001/(A-E)
Mechanical Shock	2002/(A-G)
Solderability	2003
Lead Integrity	2004/(A, B ₁ , B ₂ , D)
Vibration, Variable Frequency	2007/(A-C)
External Visual	2009
Bond Strength	2011
Resistance to Solvents	2015
Physical Dimensions	2016
Die Shear Strength	2019
PIND	2020/A, B
Nondestructive Bond Pull	2023
Lid Torque for Glass Frit Sealed Packages	2024
Adhesion of Lead Finish	2025
Random Frequency Vibration	2026
Resistance to Soldering Heat	2036/A,B
Pin Grid Destructive Lead Pull	2028
Electrostatic Discharge Sensitivity Classification	3015
Electrical Test	Note: 1

Note 1: Hi Rel Microelectronics electrical test systems are certified in compliance with MIL-STD-883 paragraph 4.5 as applicable. Hi Rel Microelectronics system is suitable to perform electrical test over military case temperature (Tcase) of 25, 125 and -55 deg C. Electrical Test suitability does not cover individual test programs. It is the responsibility of the commercial lab to obtain a record of customer approval stating that the hardware/software integration, including resolution and accuracy are adequate to meet the forcing and measurement conditions required, for the specified device type.